

General Description

The Sanrise SRT03N010LD56TR-G uses advanced split gate trench technology. It has extremely low on resistance, low gate charge and fast switching time. This device is ideal for Motor driver, BMS, DCDC converter and power management.

The SRT03N010LD56TR-G break down voltage is 30V and it has a high rugged avalanche characteristic.

The SRT03N010LD56TR-G is available in PDFN5*6 package.

Features

- Ultra Low $R_{DS(ON)} = 0.8m\Omega @ V_{GS} = 10V$.
- Ultra Low Gate Charge, $Q_g = 90nC$ typ.
- Fast switching capability
- Robust design with better EAS performance
- Non-automotive Qualified

Application

- Server / Telecom
- High Power Supply, such as DCDC converter
- Motor Driver, such as E-Tools
- BMS

Symbol

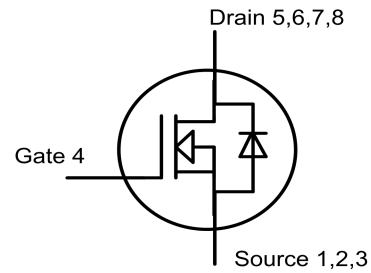
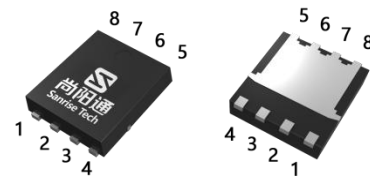


Figure 1 Symbol of SRT03N010LD56TR-G

Package Type



PDFN5*6

Figure 2 Package Type of SRT03N010LD56TR-G

Ordering Information

Circuit Type	SRT03N010L□□-□	E: Lead Free
Package	D56: PDFN5*6	G: Green
		Blank: Tube
		TR: Tape & Reel

Package	Part Number	Marking ID	Packing Type
PDFN5*6	SRT03N010LD56TR-G	SRT03N010LD56G	Tape & Reel

Absolute Maximum Ratings

Parameter		Symbol	Rating	Unit
Drain-Source Voltage		V_{DSS}	30	V
Gate-Source Voltage		V_{GSS}	±20	V
Continuous Drain Current	$T_C=25^{\circ}\text{C}$	I_D	284	A
	$T_C=100^{\circ}\text{C}$		180	
Pulsed Drain Current (Note 2)		I_{DM}	892	A
Power Dissipation ($T_C = 25^{\circ}\text{C}$)		P_D	178	W
Avalanche Energy, Single Pulse (Note 3)		E_{AS}	180	mJ
Avalanche Current, Repetitive (Note 2)		I_{AR}	60.0	A
Continuous Diode Forward Current		I_S	284	A
Diode Pulse Current		$I_{S,PULSE}$	892	A
Operating Junction Temperature		T_J	150	$^{\circ}\text{C}$
Storage Temperature		T_{STG}	-55 to 150	$^{\circ}\text{C}$
Lead Temperature (Soldering, 10 sec)		T_{LEAD}	260	$^{\circ}\text{C}$

Note:

1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.
Absolute maximum ratings are stress ratings only and functional device operation is not implied.
2. Repetitive Rating: Pulse width limited by maximum junction temperature
3. $I_{AS}= 60.0\text{A}$, $V_{DD}= 30\text{V}$, $R_G= 25\Omega$, Starting $T_J= 25^{\circ}\text{C}$

Thermal Characteristics

Parameter		Symbol	Min	Typ	Max	Unit
Thermal Resistance, Junction-to-Case	PDFN5*6	R_{thJC}		0.5	0.7	$^{\circ}\text{C}/\text{W}$
Thermal Resistance, Junction-to-Ambient	PDFN5*6	R_{thJA}			62	

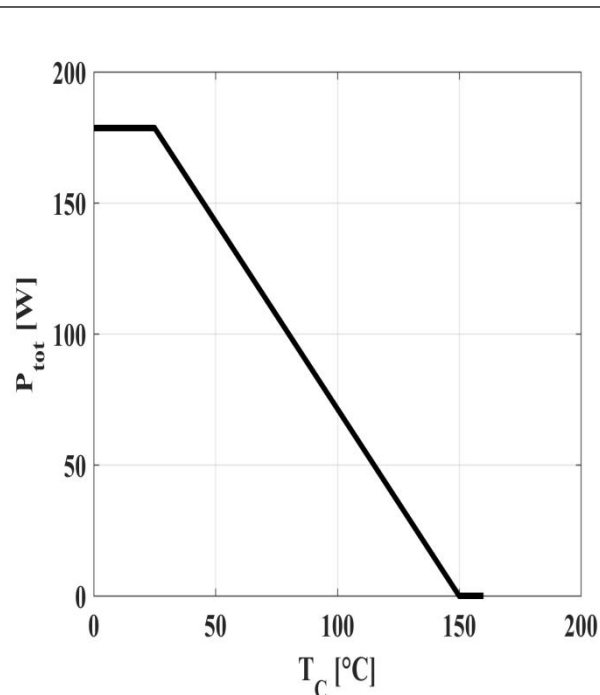
1.0mΩ, 30V, N-Channel Power MOSFET
SRT03N010LD56TR-G
Electrical Characteristics

$T_J = 25^\circ\text{C}$, unless otherwise specified.

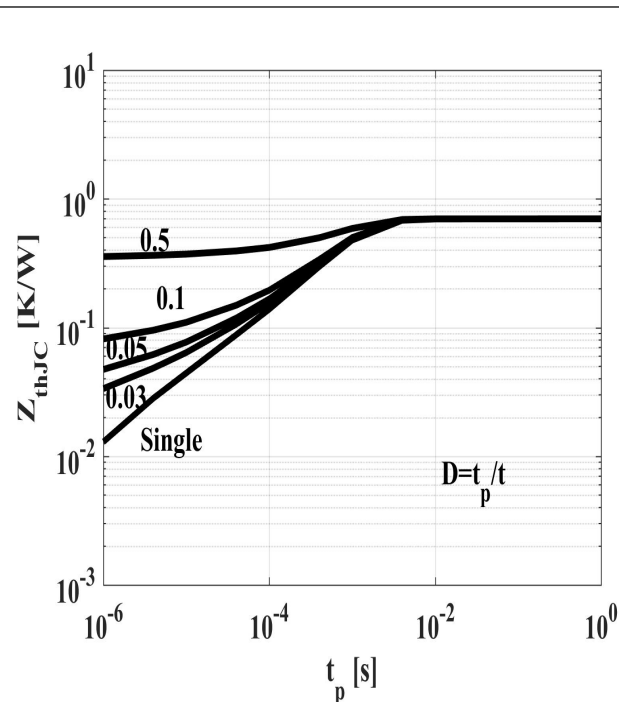
Parameter		Symbol	Test Conditions	Min	Typ	Max	Unit
Statistic Characteristics							
Drain-Source Breakdown Voltage		BV _{DSS}	V _{GS} =0V, I _D =250uA	30			V
Zero Gate Voltage Drain Current		I _{DSS}	V _{DS} =30V, V _{GS} =0V			1	uA
Gate-Body Leakage Current	Forward	I _{GSSF}	V _{GS} =20V, V _{DS} =0V			100	nA
	Reverse	I _{GSSR}	V _{GS} =-20V, V _{DS} =0V			-100	
Gate Threshold Voltage		V _{GS(TH)}	V _{DS} =V _{GS} , I _D =0.25mA	1.0	1.5	2.0	V
Static Drain-Source On-Resistance		R _{DS(ON)}	V _{GS} =10V, I _D =100A		0.8	1.0	mΩ
			V _{GS} =4.5V, I _D =20A		1.05	1.4	
Gate Resistance (Note 4)		R _G	f=1MHz, Open Drain	0.8	1.8	2.8	Ω
Dynamic Characteristics							
Input Capacitance (Note 4)		C _{ISS}	V _{DS} =15V, V _{GS} =0V, f=1MHz	5.1	7.2	9.3	nF
Output Capacitance (Note 4)		C _{OSS}		2.1	3.0	3.9	nF
Reverse Transfer Capacitance (Note 4)		C _{RSS}		150	550	950	pF
Turn-on Delay Time		t _{d(on)}	V _{DD} =15V, I _D =100A R _G =1.6Ω, V _{GS} =10V		12		ns
Rise Time		t _r			9		
Turn-off Delay Time		t _{d(off)}			50		
Fall Time		t _f			9		
Gate Charge Characteristics							
Gate to Source Charge		Q _{gs}	V _{DD} =15V, I _D =100A V _{GS} =0 to 10V		17		nC
Gate to Drain Charge		Q _{gd}			16		
Gate Charge Total (Note 4)		Q _g			90	135	
Gate Plateau Voltage		V _{plateau}			2.8		V
Reverse Diode Characteristics							
Drain-Source Diode Forward Voltage		V _{SD}	V _{GS} =0V, I _{SD} =100A		0.86	1.1	V
Reverse Recovery Time (Note 4)		t _{rr}	V _R =15V, I _F =100A dI _F /dt=100A/us		55	110	ns
Reverse Recovery Charge (Note 4)		Q _{rr}			70	140	nC
Peak Reverse Recovery Current (Note 4)		I _{rrm}			2.5		A

Note:

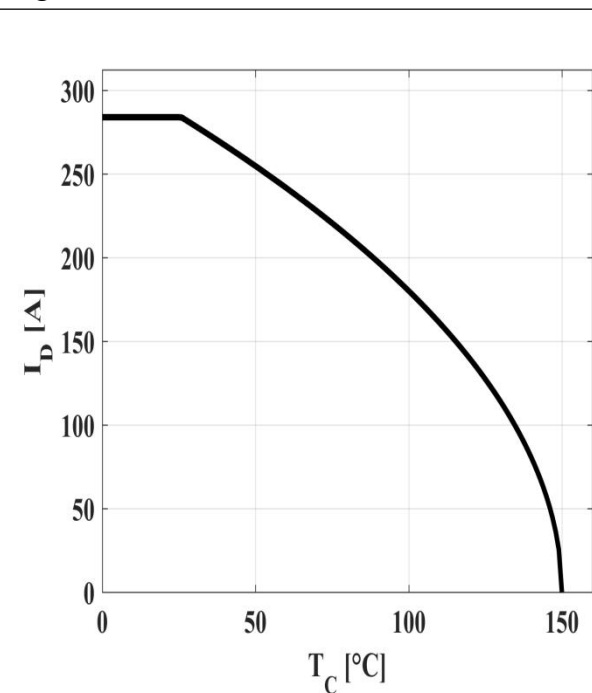
4. Defined by design. Not subject to production test.

Typical Performance Characteristics
Figure 3: Power Dissipation


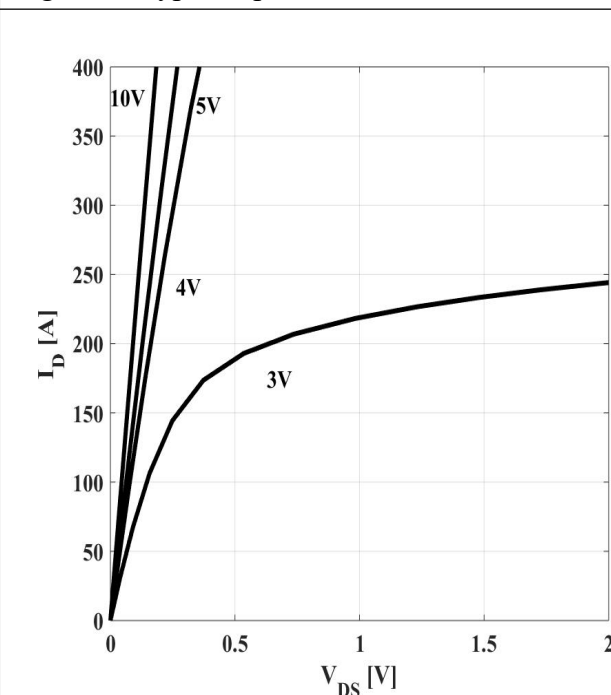
$$P_{tot}=f(T_c)$$

Figure 4: Max. Transient Thermal Impedance


$$Z_{(thJC)}=f(t_p)$$

Figure 5: Drain Current


$$I_D=f(T_c); V_{GS} \geq 10V$$

Figure 6: Typ. Output Characteristics


$$I_D=f(V_{DS}); T_j=25^{\circ}C; \text{ parameter: } V_{GS}$$

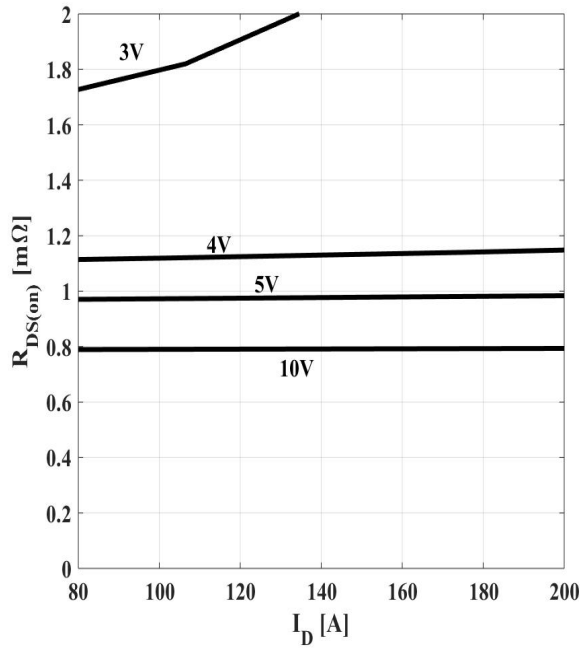
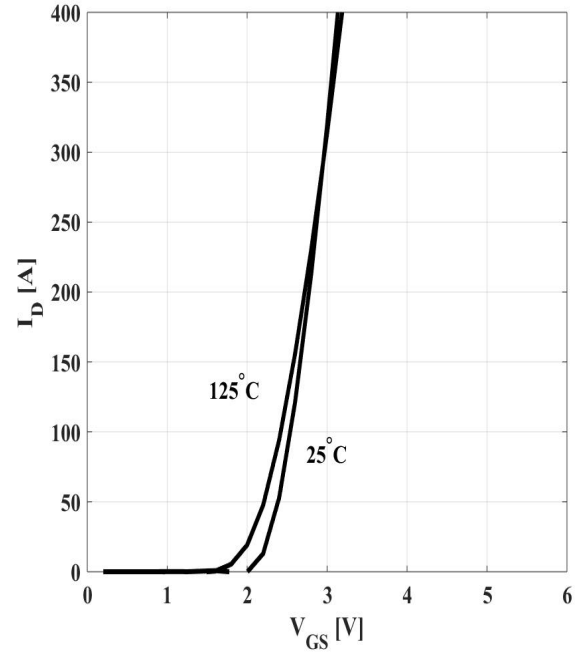
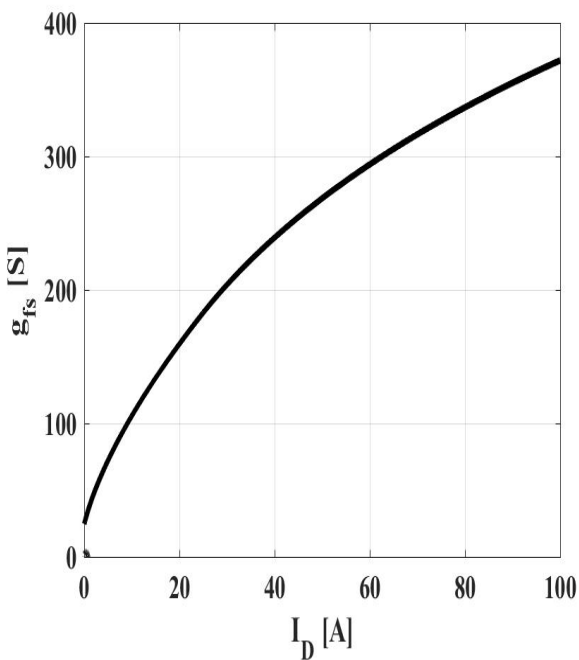
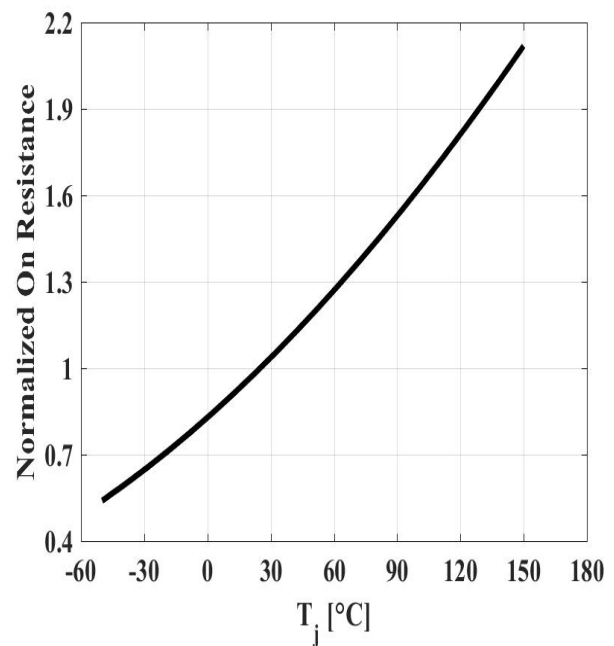
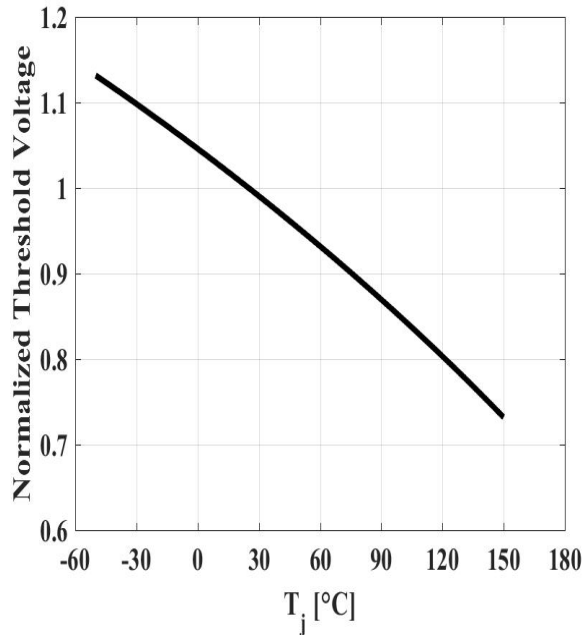
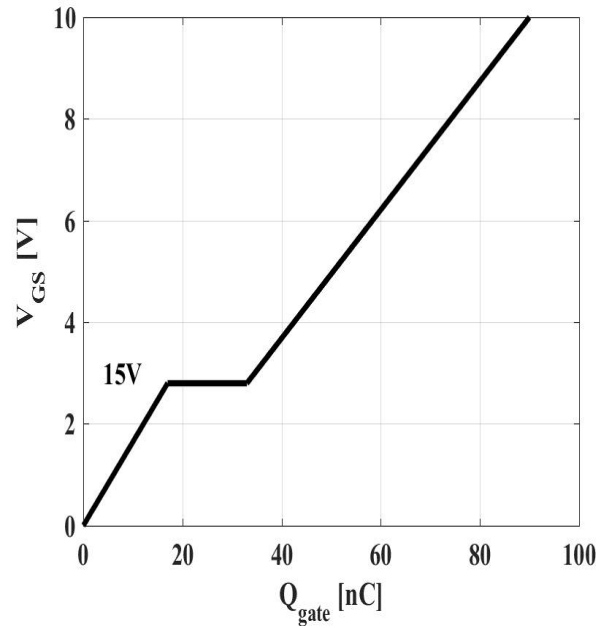
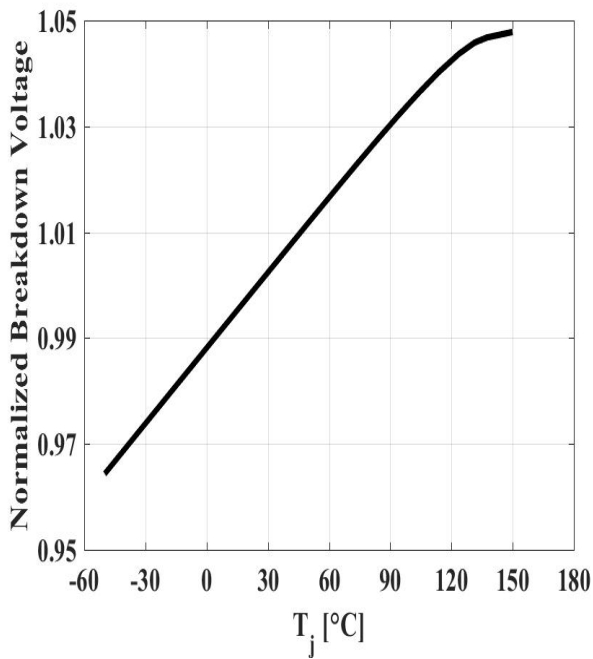
Figure7: Typ. Drain-Source On-State Resistance

 $R_{DS(ON)}=f(I_D); T_j=25^{\circ}\text{C}; \text{parameter: } V_{GS}$
Figure8: Typ. Transfer Characteristics

 $I_D=f(V_{GS}); |V_{DS}|>2|I_D|R_{DS(on)max}; \text{parameter: } T_j$
Figure 9: Typ. Forward Transconductance

 $g_{fs}=f(I_D); T_j=25^{\circ}\text{C}$
Figure 10: Typ. Drain-Source On-State Resistance

 $R_{DS(ON)}=f(T_j); I_D=100\text{A}; V_{GS}=10\text{V}$

Figure 11: Typ. Gate Threshold Voltage


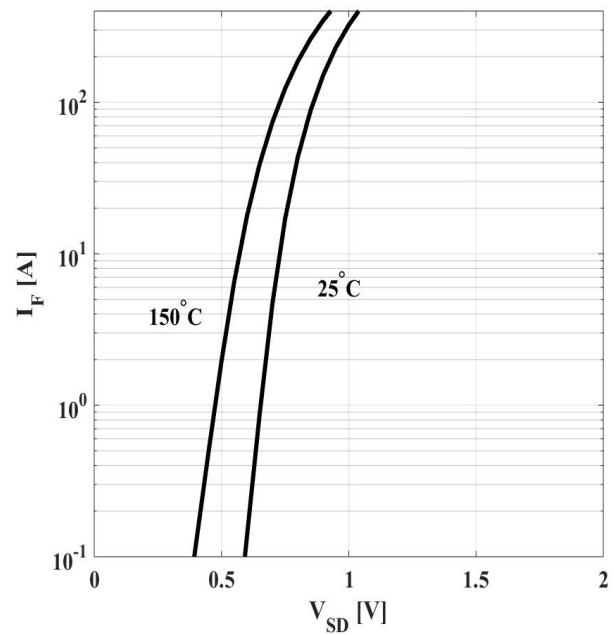
$$V_{GS(th)} = f(T_j); V_{GS} = V_{DS}; I_{DS} = 250\mu A$$

Figure 12: Typ. Gate Charge


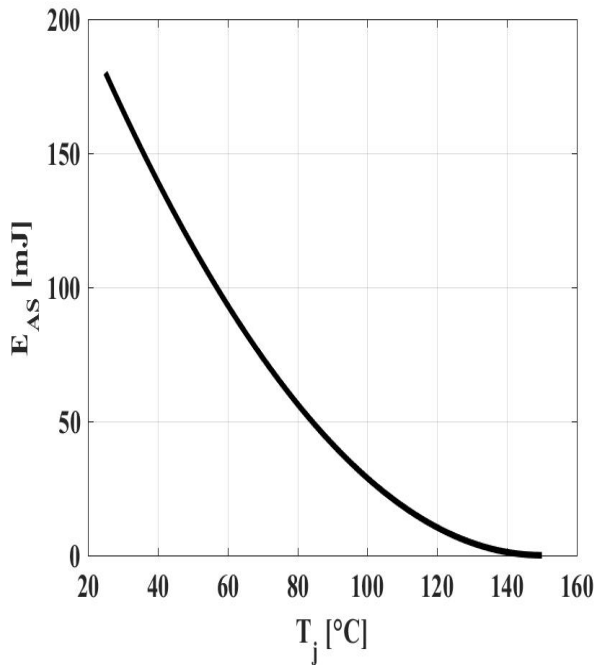
$$V_{GS} = f(Q_{gate}), I_D = 50A \text{ pulsed}$$

Figure 13: Drain-Source Breakdown Voltage


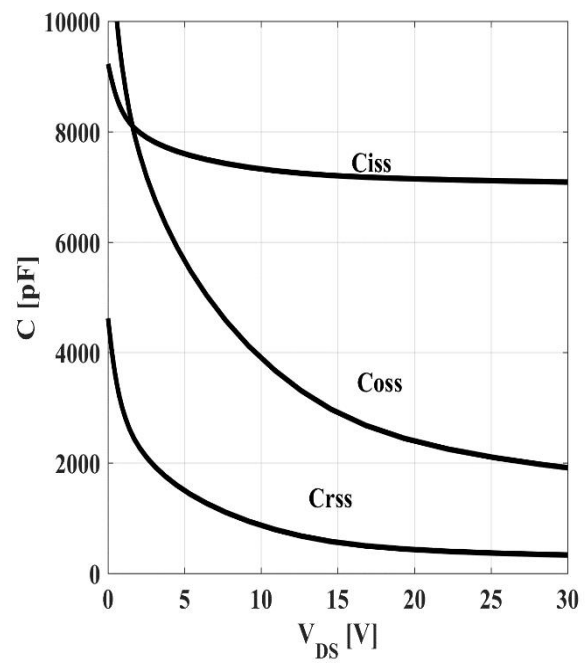
$$V_{BR(DSS)} = f(T_j); I_D = 1mA$$

Figure 14: Forward Characteristics of Reverse Diode


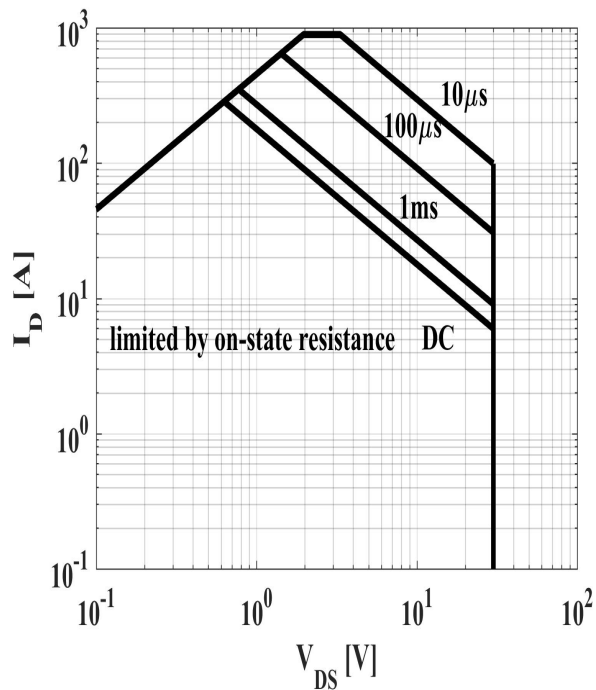
$$I_F = f(V_{SD}); \text{parameter: } T_j$$

1.0mΩ, 30V, N-Channel Power MOSFET
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Figure 15: Avalanche Energy


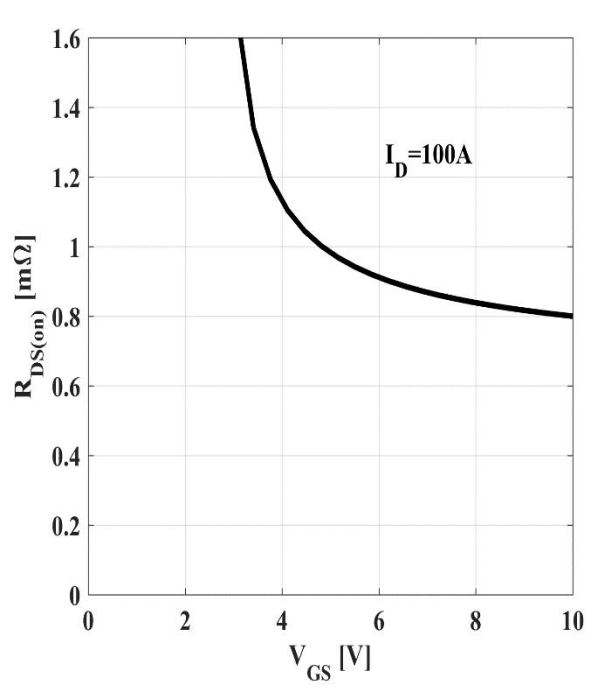
$$E_{AS}=f(T_j); I_D=60.0A; V_{DD}=15V$$

Figure 16: Typ. Capacitances


$$C=f(V_{DS}); V_{GS}=0; f=1MHz$$

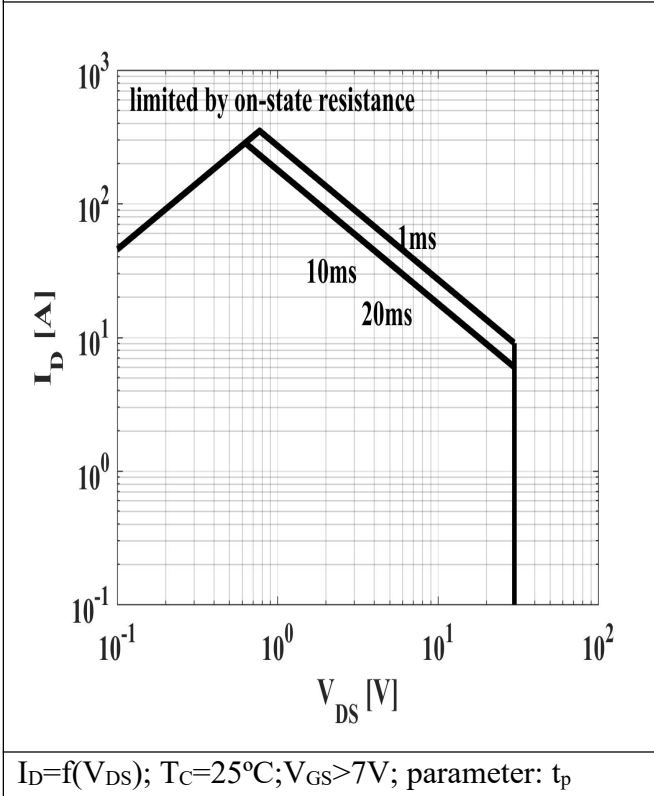
Figure 17: Safe Operating Area1


$$I_D=f(V_{DS}); T_C=25^{\circ}C; V_{GS}>7V; \text{parameter: } t_p$$

Figure 18: On-State Resistance Vs Gate-Source Voltage


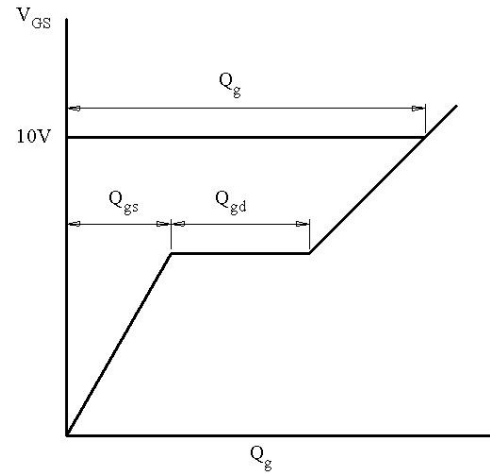
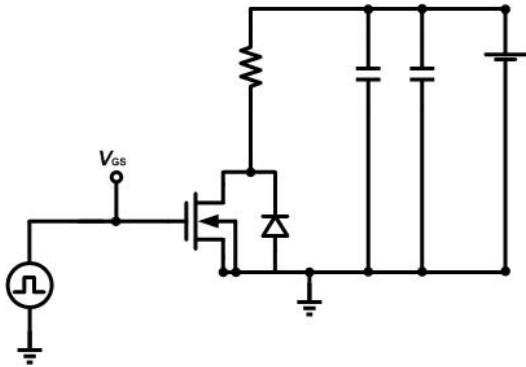
$$R_{DS(ON)}=f(V_{GS}); T_j=25^{\circ}C$$

Figure 19: Safe Operating Area2

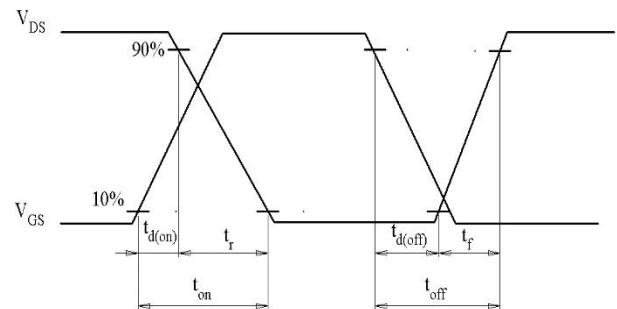
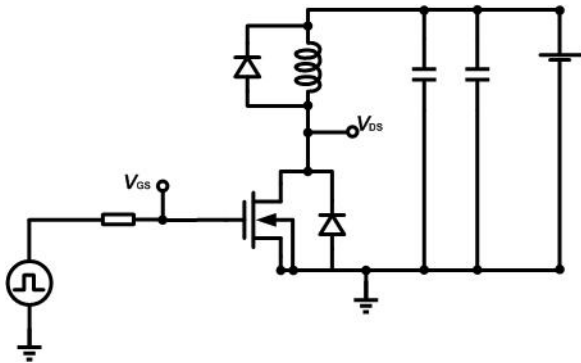


Test Circuits

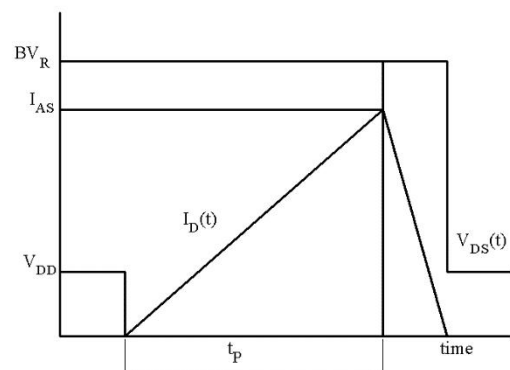
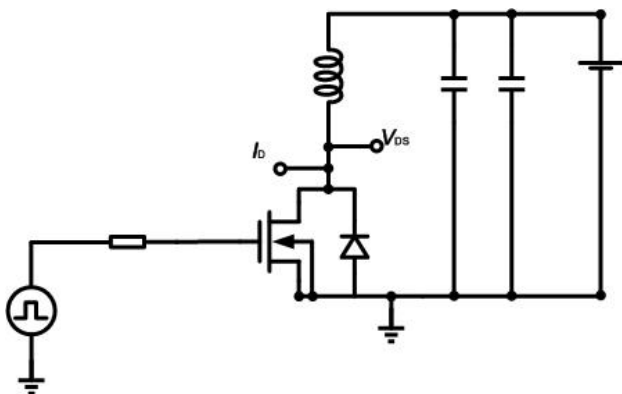
1. Gate Charge Test Circuit & Waveform



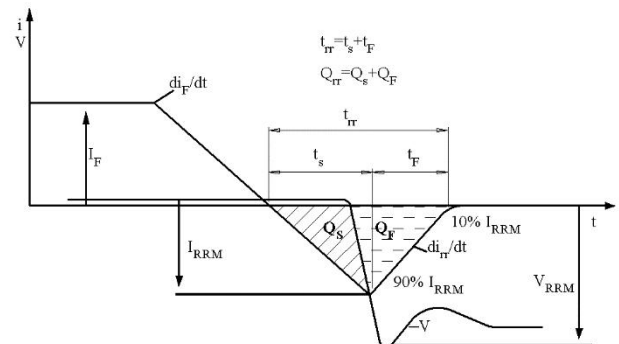
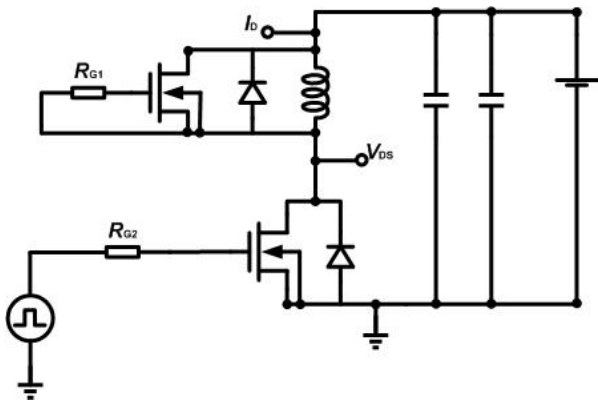
2. Switch Time Test Circuit

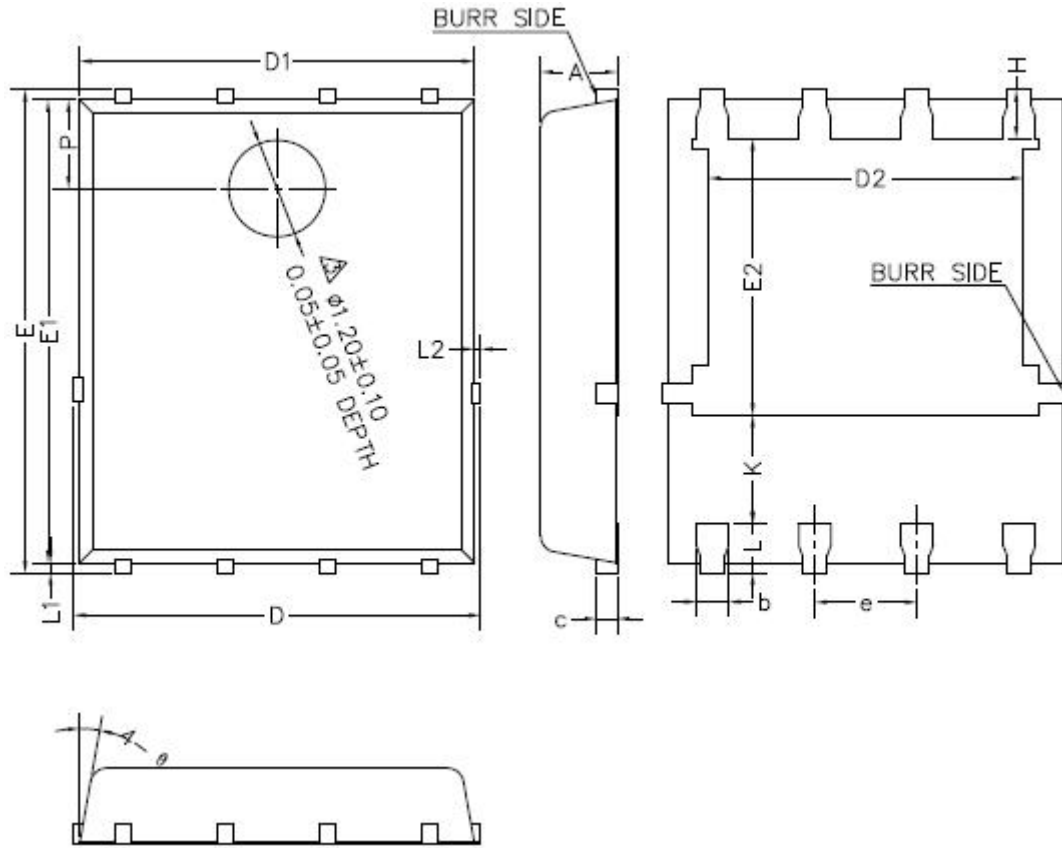


3. Unclamped Inductive Switching Test Circuit & Waveforms



4. Test Circuit and Waveform for Diode Characteristics



Mechanical Dimension
PDFN5*6-8
Unit: mm


Symbol	Dimensions(mm)		
	Min.	Typ.	Max.
A	0.90	1.10	1.20
b	0.35	0.40	0.45
c	0.21	0.25	0.34
D			5.10
D1	4.80	4.90	5.00
D2	3.91	4.01	4.11
e	1.17	1.27	1.37
E	5.90	6.00	6.10
E1	5.70	5.75	5.80
E2	3.34	3.44	3.54
H	0.51	0.61	0.71
K	1.10		
L	0.51	0.61	0.71
L1	0.06	0.13	0.20
L2			0.10
P	1.00	1.10	1.20
θ	8°	10°	12°



Sanrise Technology Limited Company

<http://www.sanrise-tech.com>

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